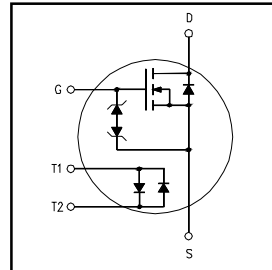


# IRLBD59N04E

HEXFET® Power MOSFET

- Integrated Temperature Sensing Diode
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fully Avalanche Rated
- Zener Gate Protected

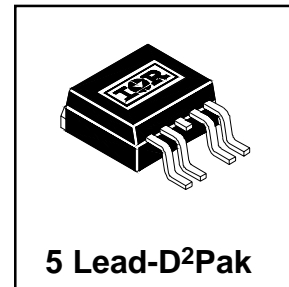


$V_{DSS} = 40V$
$R_{DS(on)} = 0.018\Omega$
$I_D = 59A\text{⑤}$

## Description

The IRLBD59N04E is a 40V, N-channel HEXFET® power MOSFET with gate protection provided by integrated back to back zener diodes. Temperature sensing is given by the change in forward voltage drop of two antiparallel electrically isolated poly-silicon diodes.

The IRLBD59N04E provides cost effective temperature sensing for system protection along with the quality and ruggedness you expect from a HEXFET power MOSFET.



## Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	59⑥	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	41	
$I_{DM}$	Pulsed Drain Current ①	230	
$P_D @ T_C = 25^\circ C$	Power Dissipation	130	W
	Linear Derating Factor	0.89	W/°C
$V_{GS}$	Gate-to-Source Voltage	$\pm 10$	V
$E_{AS}$	Single Pulse Avalanche Energy②	340	mJ
$I_{AR}$	Avalanche Current③	35	A
$E_{AR}$	Repetitive Avalanche Energy④	13	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.6	V/ns
$I_G$	$V_{GS}$ Clamp Current	$\pm 50$	mA
$V_{ESD}$	Electrostatic Voltage Rating⑥	$\pm 2.0$	kV
$T_J$	Operating Junction and	-55 to + 175	°C
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

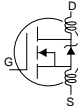
## Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	1.12	°C/W
$R_{\theta JA}$	Junction-to-Ambient ( PCB Mounted,steady-state)**	—	40	

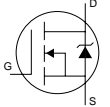
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## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

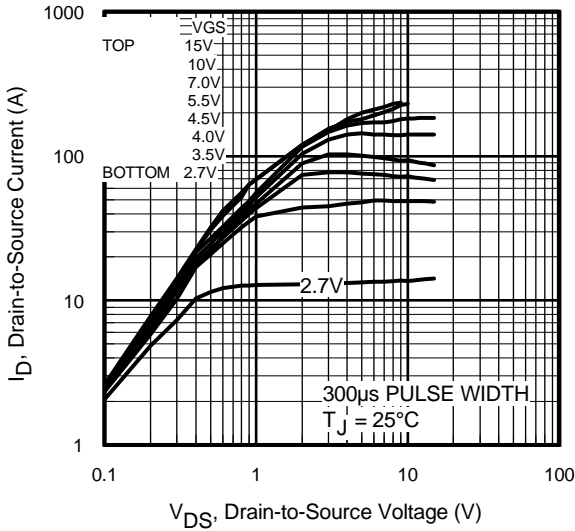
	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	40	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.044	—	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—	—	0.018	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 35A ④
		—	—	0.021		V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 30A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0	—	2.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
V <sub>GS</sub>	Clamp Voltage	10	—	20	V	I <sub>GSS</sub> = 20μA
g <sub>fs</sub>	Forward Transconductance	29	—	—	S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 35A
I <sub>DSS</sub>	Drain-to-Source Leakage Current	—	—	25	μA	V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V
		—	—	250		V <sub>DS</sub> = 32V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	—	—	1.0	μA	V <sub>GS</sub> = 5.0V
	Gate-to-Source Reverse Leakage	—	—	-1.0		V <sub>GS</sub> = -5.0V
Q <sub>g</sub>	Total Gate Charge	—	—	50	nC	I <sub>D</sub> = 35A
Q <sub>gs</sub>	Gate-to-Source Charge	—	—	13		V <sub>DS</sub> = 32V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	—	—	18		V <sub>GS</sub> = 5.0V, See Fig. 6 and 13 ④
t <sub>d(on)</sub>	Turn-On Delay Time	—	7.8	—	ns	V <sub>DD</sub> = 20V
t <sub>r</sub>	Rise Time	—	84	—		I <sub>D</sub> = 35A
t <sub>d(off)</sub>	Turn-Off Delay Time	—	33	—		R <sub>G</sub> = 5.1Ω,
t <sub>f</sub>	Fall Time	—	67	—		V <sub>GS</sub> = 5.0V, See Fig.10 ④
L <sub>D</sub>	Internal Drain Inductance	—	2.0	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L <sub>S</sub>	Internal Source Inductance	—	5.0	—		
C <sub>iss</sub>	Input Capacitance	—	2190	—	pF	V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance	—	670	—		V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance	—	130	—		f = 1.0MHz, See Fig. 5

## Source-Drain Ratings and Characteristics

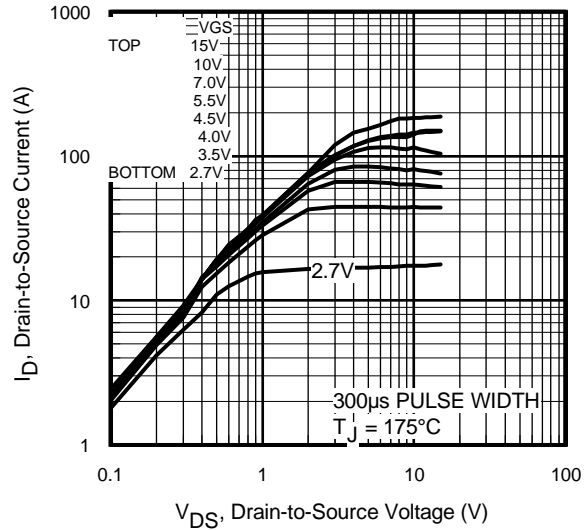
	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	59⑥	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	230		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 35A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	57	86	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 35A
Q <sub>rr</sub>	Reverse Recovery Charge	—	84	130	nC	di/dt = 100A/μs ④
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

## Sense Diode Rating

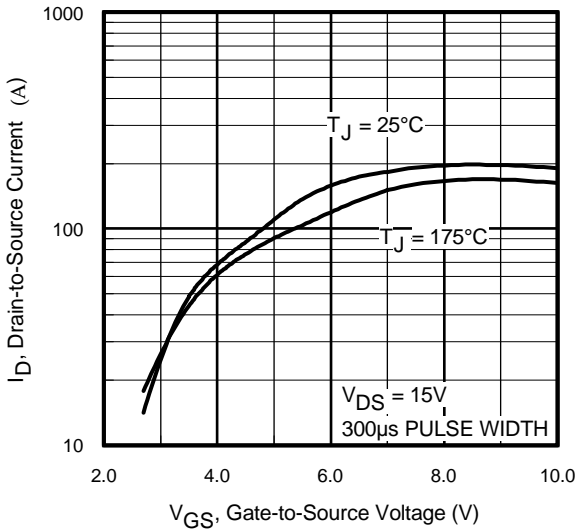
	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>FM</sub>	Sense Diode Maximum Voltage Drop	675	—	725	mV	I <sub>F</sub> = 250μA, T <sub>J</sub> = 25°C
ΔV <sub>F</sub> /ΔT <sub>J</sub>	Sense Diode Temperature Coefficient	-1.30	-1.40	-1.58	mV/°C	I <sub>F</sub> = 250μA, (T <sub>J</sub> = 25°C and 160°C)



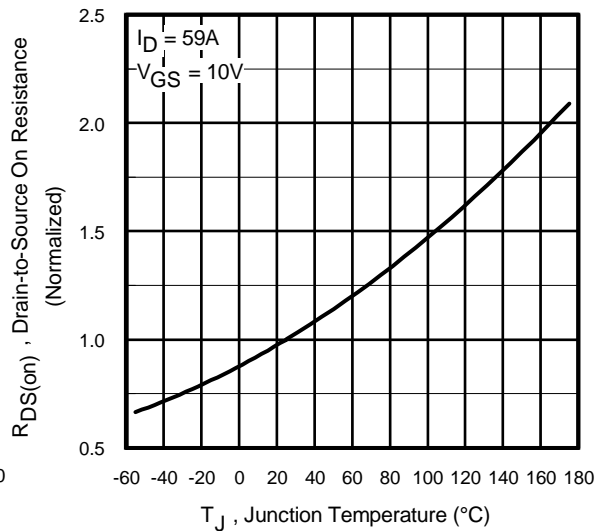
**Fig 1.** Typical Output Characteristics



**Fig 2.** Typical Output Characteristics



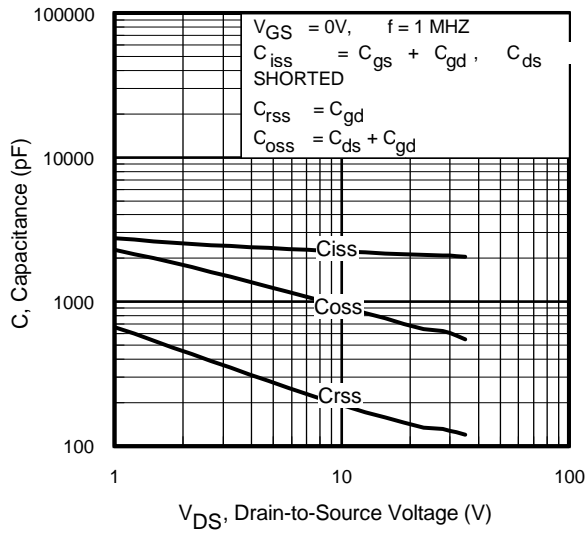
**Fig 3.** Typical Transfer Characteristics



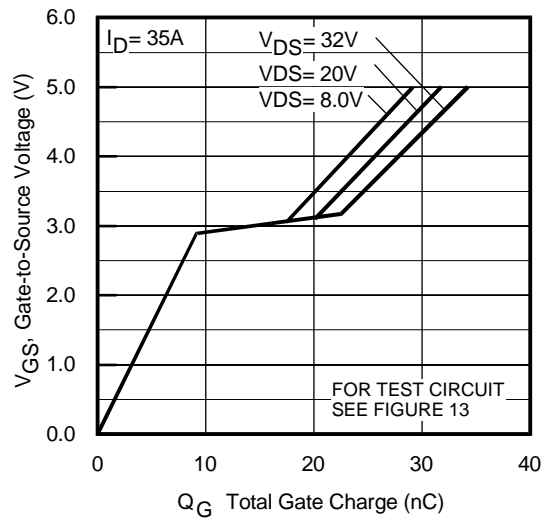
**Fig 4.** Normalized On-Resistance Vs. Temperature

# IRLBD59N04E

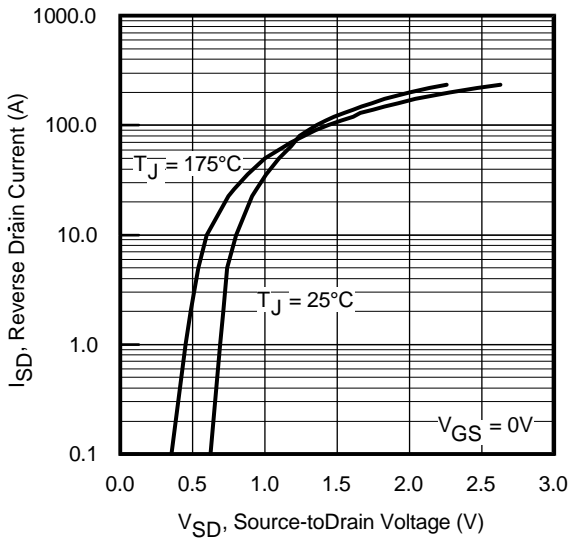
International  
**IR** Rectifier



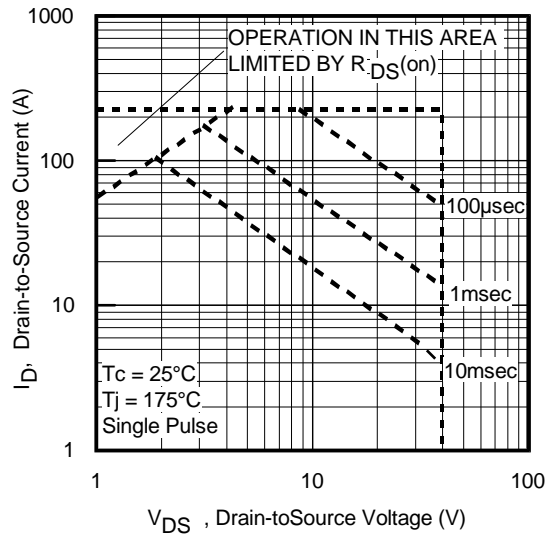
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 8.** Maximum Safe Operating Area

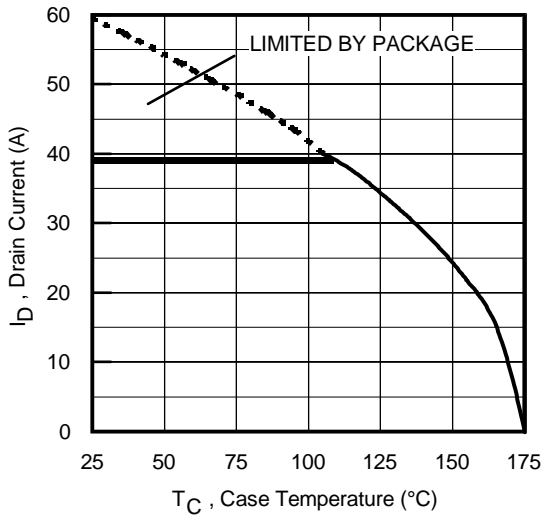


Fig 9. Maximum Drain Current Vs. Case Temperature

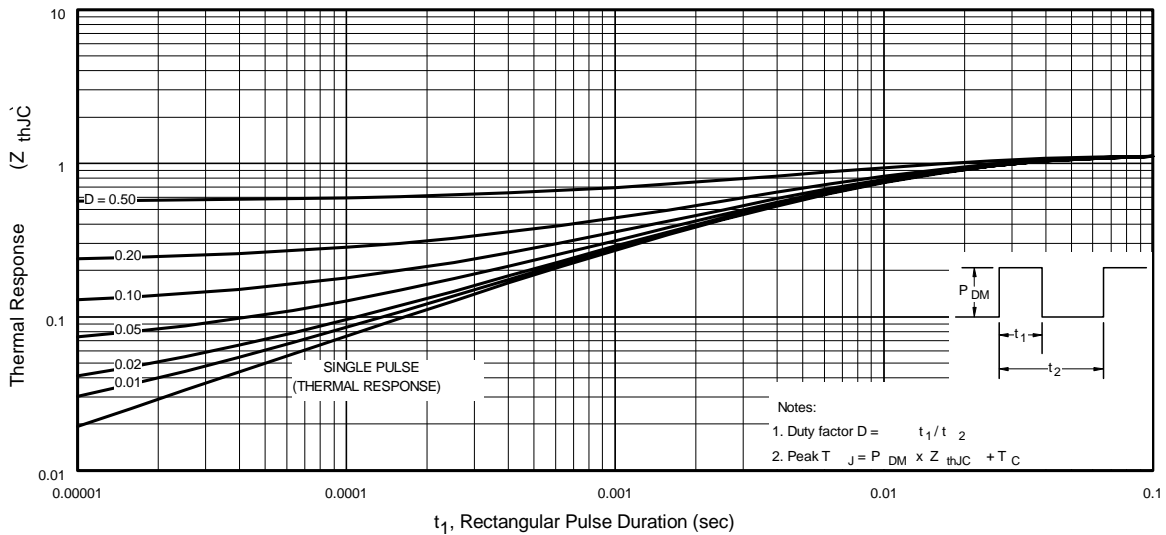
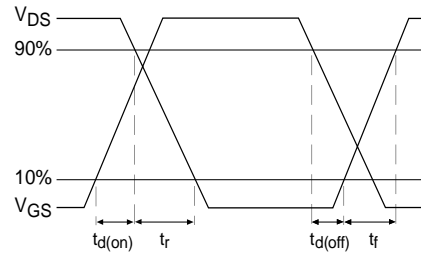
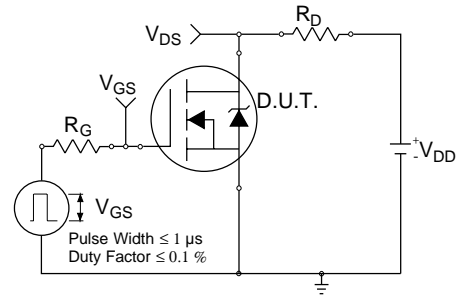
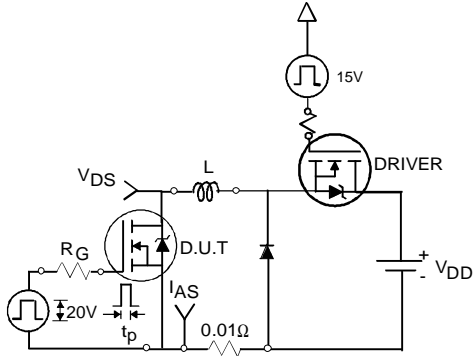


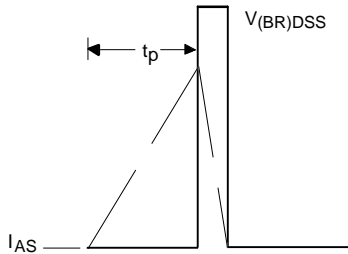
Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

# IRLBD59N04E

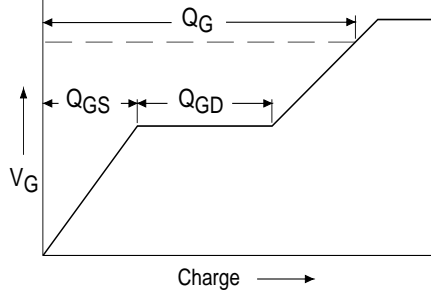
International  
**IR** Rectifier



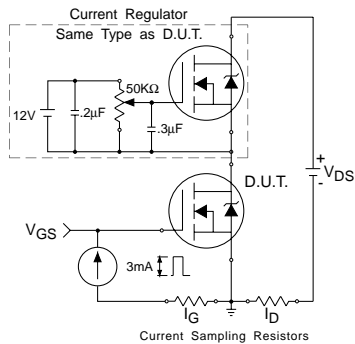
**Fig 12a.** Unclamped Inductive Test Circuit



**Fig 12b.** Unclamped Inductive Waveforms

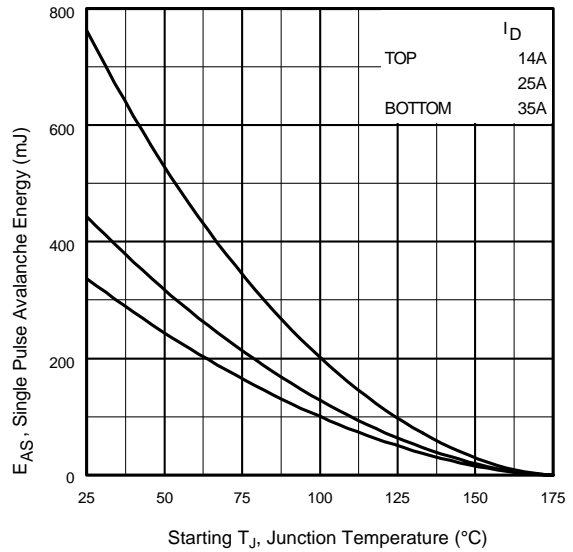


**Fig 13a.** Basic Gate Charge Waveform

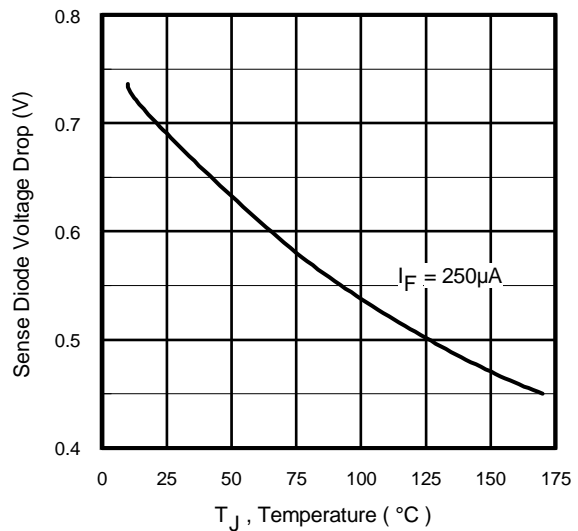


**Fig 13b.** Gate Charge Test Circuit

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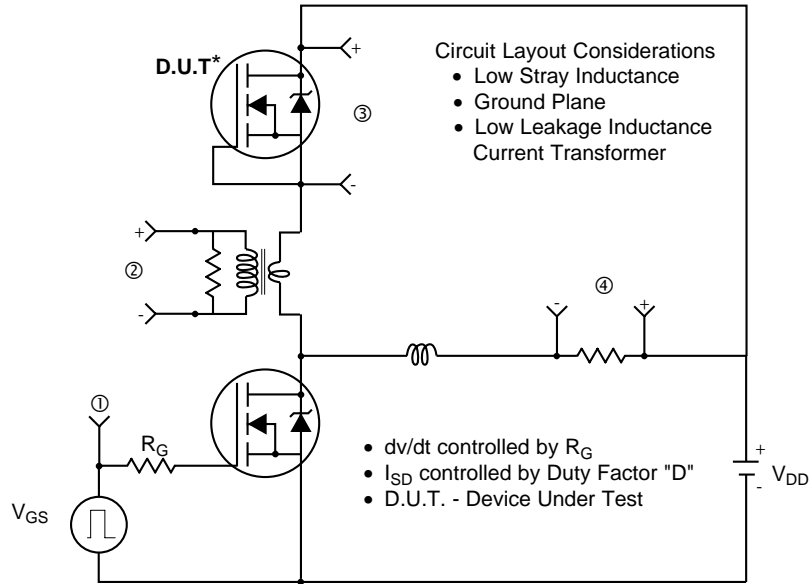
**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current



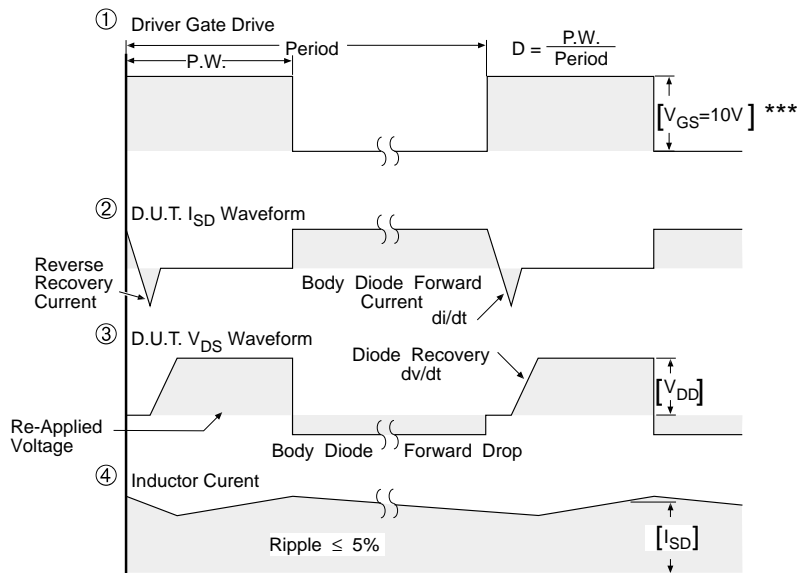
**Fig 14.** Sense Diode Voltage Drop Vs. Temperature

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**Peak Diode Recovery dv/dt Test Circuit**



\* Reverse Polarity of D.U.T for P-Channel



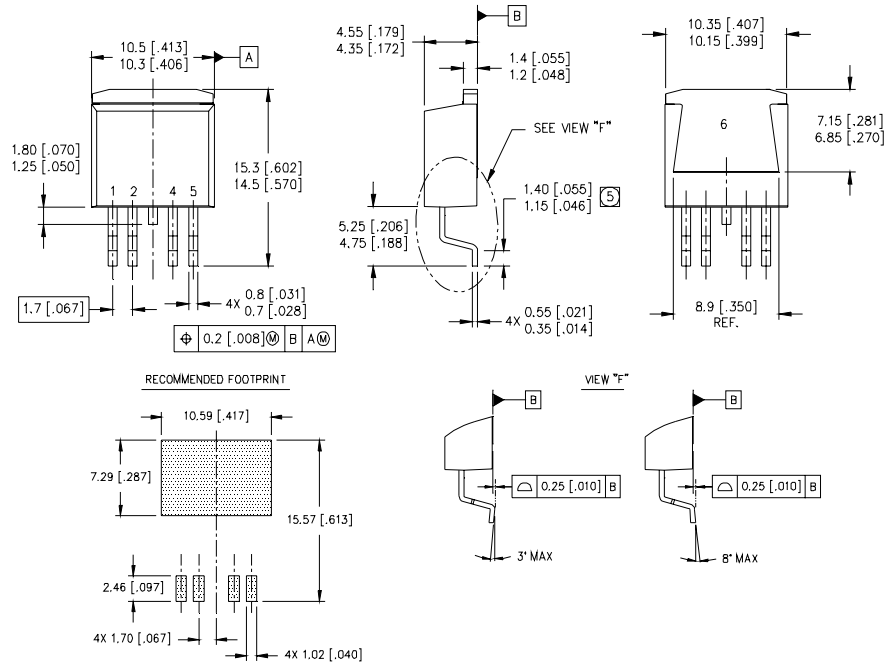
\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

**Fig 15.** For N-channel HEXFET® power MOSFETs

# IRLBD59N04E

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## Case Outline 5 Lead-D<sup>2</sup>Pak (SMD-220)



### NOTES:

1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
4. OUTLINE SIMILAR TO JEDEC OUTLINE SERIES TO-263.
- ⑤ DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.

### PIN ASSIGNMENTS

- 1 - G - GATE
- 2 - T1 - ANODE
- 3 - D - DRAIN
- 4 - T2 - CATHODE
- 5 - S - SOURCE

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 0.55\text{mH}$   
 $R_G = 25\Omega$ ,  $I_{AS} = 35\text{A}$ . (See Figure 12)
- ③  $I_{SD} \leq 35\text{A}$ ,  $di/dt \leq 150\text{A}/\mu\text{s}$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  
 $T_J \leq 175^\circ\text{C}$
- ④ Pulse width  $\leq 400\mu\text{s}$ ; duty cycle  $\leq 2\%$ .
- ⑤ Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 39A
- ⑥  $C = 100\text{pF}$ ,  $R = 1.5\text{k}\Omega$

\*\* When mounted on 1" square PCB ( FR-4 or G-10 Material ).  
For recommended soldering techniques refer to application note #AN-994.

Data and specifications subject to change without notice.  
This product has been designed and qualified for the Automotive [Q101] market.  
Qualification Standards can be found on IR's Web site.

International  
**IR** Rectifier

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105  
TAC Fax: (310) 252-7903

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Note: For the most current drawings please refer to the IR website at:  
<http://www.irf.com/package/>